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	AB	3,6	614,345	10/19/71	Quinn						_
	AC	3,6	683,306	8/872	Bulthius et a	al.					
	AD	40	332,081	6/1.82	Francis						_
	AE	14	518,944	מיונא	Faris						
	AF	4,7	703,555	11/3/87	Hubner				X 7		_
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	AH	5,3	147,8 69	920-94	Shie et al.						-
	AÌ	5,4	106,109	4/11.95	Whitney			7			
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1	AU	-		"Silicon Processing for the	VLSI Ere"; Volu	ime 1 - Process Technology,	Second Edition; S	i, Wolf et al.; 2000; pps 22-1	11 and pps. 841	-845.		-	
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